

MAHARASHTRA STATE BOARD OF VOCATIONAL EXAMINATIONS, MUMBAI

Examination, July, 2014

CERTIFICATE COURSE IN MOBILE REPAIRING AND SERVICING

[Ἑβρ—3 ἰεε^οε]

(BEthÉ NÖÉ—100)

$$j\left(\frac{\partial}{\partial t} + \nabla \cdot \vec{v}\right) + \nabla \cdot (\vec{v} \otimes \vec{v}) = -\nabla p + \mu \Delta \vec{v}$$

NĚÉ

1. $\frac{V_{out}}{V_{in}}$ for the Component SEE the V_{in} NAND and NOR Logic Gates 50
if the V_{in} is the same as the V_{out} .
2. If the V_{in} is the same as the V_{out} , it is Good if the Faulty 30
+ the V_{in} is the same as the V_{out} :-
(+) MCT 2E (+) 1 N 4004
(-) 1000 MFD / 25 V (-) 4 N 35
(<) 5000 MFD / 25 V.
3. + the V_{in} . 10
4.] the V_{in} . 10

(ENGLISH)

[TIME ALLOWED — 3 HOURS]

(MARKS — 100)

**FUNDAMENTAL OF ELECTRONICS AND MOBILE PHONE
TECHNOLOGY (PRACTICAL-I)**

Marks

- | | | |
|----|--|----|
| 1. | Assemble and verify the NAND and NOR Logic Gates using given components. | 50 |
| 2. | Identify and Test the following components and record the observation as Good or Faulty :—
<div style="display: flex; justify-content: space-between; margin-top: 10px;"> <div style="width: 45%;"> <p>(a) MCT 2E</p> <p>(c) 1000 MFD / 25 V</p> <p>(e) 5000 MFD / 25 V.</p> </div> <div style="width: 45%;"> <p>(b) 1 N 4004</p> <p>(d) 4 N 35</p> </div> </div> | 30 |
| 3. | Oral. | 10 |
| 4. | Term Work. | 10 |